

Search Notes

Application/Control No.

10/698,856

Examiner

Phi D. A

Applicant(s)/Patent under
Reexamination

SMEED ET AL.

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
see attached		